



<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		<b>Complete if Known</b>	
		Application Number	10/644,644
		Filing Date	August 19, 2003
		First Named Inventor	Henley, Francois J.
		Art Unit	Not Yet Assigned <u>2823</u>
Sheet 1	of 12	Examiner Name	Not Yet Assigned <u>H. LEE</u>
		Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS+					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Lee	1	2,614,055	10/1952	Senareclens	
	2	3,117,022	01/1964	Bronson et al.	
	3	3,225,820	12/1995	Riordan	
	4	3,390,033	06/1968	Brown	
	5	3,551,213	12/1970	Boyle	
	6	3,770,499	10/1973	Crowe et al.	
	7	3,786,359	01/1974	King	
	8	3,806,380	04/1974	Kitada et al.	
	9	3,832,219	08/1974	Nelson et al.	
	10	3,900,636	08/1975	Curry et al.	
	11	3,901,423	08/1975	Hillberry et al.	
	12	3,915,757	10/1975	Engel	
	13	3,946,334	03/1976	Yonezu et al.	
	14	3,957,107	05/1976	Altoz et al.	
	15	3,993,909	11/1976	Drews et al.	
	16	4,006,340	02/1977	Gorinas	
	17	4,039,416	08/1977	White	
	18	4,053,335	10/1977	Hu	
	19	4,074,139	02/1978	Pankove	
	20	4,107,350	08/1978	Berg et al.	
	21	4,108,751	08/1978	King	
	22	4,116,751	09/1978	Zaromb	
	23	4,121,334	10/1978	Wallis	
	24	4,170,662	10/1979	Weiss et al.	
	25	4,216,906	08/1980	Olsen et al.	
	26	4,237,601	12/1980	Woolhouse et al.	
	27	4,244,348	01/1981	Wilkes	
	28	4,252,837	02/1981	Auton	
Lee	29	4,255,208	03/1981	Deutscher et al.	

Examiner Signature	<u>Hee Min Lee</u>	Date Considered	<u>6/22/05</u>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Kind Codes of U.S. Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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**INFORMATION DISCLOSURE  
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Sheet 2 of 12

**Complete if Known**

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Lee	30	4,274,004	06/1981	Kanai		
	31	4,342,631	08/1982	White et al.		
	32	4,346,123	08/1982	Kaufmann		
[Vertical line]	33	4,361,600	11/1982	Brown		
	34	4,368,083	01/1983	Bruel et al.		
	35	4,375,125	03/1983	Byatt		
	36	4,412,868	11/1983	Brown et al.		
	37	4,452,644	06/1984	Bruel et al.		
	38	4,468,309	08/1984	White		
	39	4,471,003	09/1984	Cann		
	40	4,486,247	12/1984	Ecer et al.		
	41	4,490,190	12/1984	Speri		
	42	4,500,563	02/1985	Ellenberger et al.		
	43	4,508,056	04/1985	Bruel et al.		
	44	4,536,657	08/1985	Bruel		
	45	4,539,050	09/1985	Kramler et al.		
	46	4,566,403	01/1986	Fournier		
	47	4,567,505	01/1986	Pease et al.		
	48	4,568,563	02/1986	Jackson et al.		
	49	4,585,945	04/1986	Bruel et al.		
	50	4,645,546	02/1987	Matsushita		
	51	4,684,535	08/1987	Heinecke et al.		
	52	4,704,302	11/1987	Bruel et al.		
	53	4,706,377	11/1987	Shuskus		
	54	4,717,683	01/1988	Parrillo et al.		
	55	4,727,047	02/1988	Bozler et al.		
	56	4,764,394	08/1988	Conrad		
	Lee	57	4,766,086	08/1988	Ohshima et al.	
		58	4,837,172	06/1989	Mizuno et al.	

Examiner Signature	<i>Asw. Ming Lu</i>	Date Considered	6/22/05
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Sheet 3 of 12

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Attorney Docket Number	018419-000183US

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		Number	Kind Code <sup>2</sup> (if known)			
Lee	59	4,846,928		07/1989	Dolins et al.	
	60	4,847,792		07/1989	Barna et al.	
	61	4,853,250		08/1989	Boulos et al.	
	62	4,883,561		11/1989	Gmitter et al.	
	63	4,887,005		12/1989	Rough et al.	
	64	4,891,329		01/1990	Reisman et al.	
	65	4,894,709		01/1990	Phillips et al.	
	66	4,931,405		06/1990	Kamijo et al.	
	67	4,948,458		08/1990	Ogle	
	68	4,952,273		08/1990	Popov	
	69	4,956,693		09/1990	Sawahata et al.	
	70	4,960,073		10/1990	Suzuki et al.	
	71	4,982,090		01/1991	Wittmaack	
	72	4,983,251		01/1991	Haisma et al.	
	73	4,996,077		02/1991	Moslehi et al.	
	74	5,015,353		05/1991	Hubler et al.	
	75	5,034,343		07/1991	Rouse et al.	
	76	5,070,040		12/1991	Pankove	
	77	5,082,793		01/1992	Li	
	78	5,102,821		04/1992	Moslehi	
	79	5,110,748		05/1992	Sarma	
	80	5,133,826		07/1992	Dandl	
	81	5,162,241		11/1992	Mori et al.	
	82	5,196,355		03/1993	Wittkower	
	83	5,198,371		03/1993	Li	
	84	5,202,095		04/1993	Houchin et al.	
	85	5,203,960		04/1993	Dandl	
	86	5,206,749		04/1993	Zavracky et al.	
Lee	87	5,213,451		05/1993	Frank	
Examiner Signature	Kris Mary Lee			Date Considered	6/22/05	

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Sheet 4 of 12

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Attorney Docket Number	018419-000183US

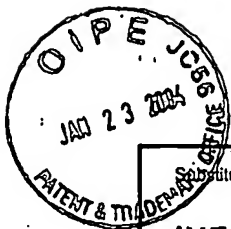
**U.S. PATENT DOCUMENTS+**

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Lee	88	5,234,529	08/1993	Johnson	
	89	5,234,535	08/1993	Beyer et al.	
	90	5,242,861	09/1993	Inaba	
	91	5,250,328	10/1993	Otto	
	92	5,252,178	10/1993	Moslehi	
	93	5,256,562	10/1993	Vu et al.	
	94	5,258,320	11/1993	Zavracky et al.	
	95	5,258,325	11/1993	Spitzer et al.	
	96	5,269,880	12/1993	Jolly et al.	
	97	5,273,610	12/1993	Thomas, III et al.	
	98	5,277,748	01/1994	Sakaguchi et al.	
	99	5,303,574	04/1994	Matossian et al.	
	100	5,304,509	04/1994	Sopori	
	101	5,308,776	05/1994	Gotou	
	102	5,317,236	05/1994	Zavracky et al.	
	103	5,342,472	08/1994	Imahashi et al.	
	104	5,344,524	09/1994	Sharma et al.	
	105	5,354,381	10/1994	Sheng	
	106	5,362,671	11/1994	Zavracky et al.	
	107	5,363,603	11/1994	Miller et al.	
	108	5,368,710	11/1994	Chen et al.	
	109	5,370,765	12/1994	Dandl	
	110	5,374,564	12/1994	Bruehl	
	111	5,376,560	12/1994	Aronowitz et al.	
	112	5,377,031	12/1994	Vu et al.	
	113	5,404,079	04/1995	Ohkuni et al.	
	114	5,405,480	04/1995	Benzing et al.	
	115	5,411,592	05/1995	Ovshinsky et al.	
Lee	116	5,413,679	05/1995	Godbey	

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Considered

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PTO/SB/08A (08-03)

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		Filing Date	August 19, 2003		
		First Named Inventor	Henley, Francois J.		
		Art Unit	Not Yet Assigned 2823		
		Examiner Name	Not Yet Assigned H. LEE		
Sheet	5	of	12	Attorney Docket Number	018419-000183US

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Lee	117	5,435,880	07/1995	Minato et al.	
	118	5,438,241	08/1995	Zavracky et al.	
I	119	5,443,661	08/1995	Oguro et al.	
	120	5,444,557	08/1995	Spitzer et al.	
	121	5,459,016	10/1995	Debe et al.	
	122	5,475,514	12/1995	Salerno et al.	
	123	5,476,691	12/1995	Komvopoulos et al.	
	124	5,480,842	01/1996	Clifton et al.	
	125	5,487,785	01/1996	Horiike et al.	
	126	5,494,835	02/1996	Bruel	
	127	5,504,328	04/1996	Bonser	
	128	5,528,397	06/1996	Zavracky et al.	
	129	5,539,245	06/1996	Imura et al.	
	130	5,558,718	09/1996	Leung	
	131	5,559,043	09/1996	Bruel	
	132	5,569,620	10/1996	Linn et al.	
	133	5,581,385	12/1996	Spitzer et al.	
	134	5,585,304	12/1996	Hayashi et al.	
	135	5,611,855	03/1997	Wijaranakula	
	136	5,643,834	07/1997	Harada et al.	
	137	5,653,811	08/1997	Chan	
	138	5,705,421	01/1998	Matsushita et al.	
	139	5,710,057	01/1998	Kenney	
	140	5,714,395	02/1998	Bruel	
	141	5,744,852	04/1998	Linn et al.	
	142	5,753,560	05/1998	Hong et al.	
	143	5,755,914	05/1998	Yonchara	
	144	5,763,319	06/1998	Ling et al.	
Lee	145	5,783,022	07/1998	Cha et al.	
Examiner Signature	Ksien Ming Lee		Date Considered	6/22/05	

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Sheet 6 of 12

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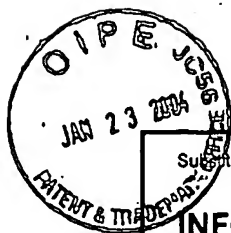
**U.S. PATENT DOCUMENTS+**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
Lee	146	5,804,086	09/1998	Bruel	
	147	5,821,158	10/1998	Shishiguchi	
	148	5,824,595	10/1998	Igel et al.	
	149	5,827,751	10/1998	Nuyen	
	150	5,840,590	11/1998	Myers, Jr. et al.	
	151	5,854,123	12/1998	Sato et al.	
	152	5,869,387	02/1999	Sato et al.	
	153	5,877,070	03/1999	Goesele et al.	
	154	5,882,987	03/1999	Srikrishnan	
	155	5,909,627	06/1999	Egloff	
	156	5,920,764	07/1999	Hanson et al.	
	157	5,953,622	09/1999	Lee et al.	
	158	5,966,620	10/1999	Sakaguchi et al.	
	159	5,985,742	11/1999	Henley et al.	
	160	5,993,677	11/1999	Biasse et al.	
	161	5,994,207	11/1999	Henley et al.	
	162	6,010,579	01/2000	Henley et al.	
	163	6,013,563	01/2000	Henley et al.	
	164	6,020,252	02/2000	Aspar et al.	
	165	6,033,974	03/2000	Henley et al.	
	166	6,048,411	04/2000	Henley et al.	
	167	6,077,383	06/2000	Laporte	
	168	6,083,324	07/2000	Henley	
	169	6,120,597	09/2000	Levy et al.	
	170	6,150,239	11/2000	Goesele et al.	
	171	6,159,824	12/2000	Henley et al.	
	172	6,171,965	01/2001	Kang et al.	
Lee	173	6,184,111	02/2001	Henley et al.	

Examiner  
Signature*Kevin Ming Lee*Date  
Considered

6/22/05

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Lu	174	6,190,998	02/2001	Bruel et al.	
Lu	175	6,191,007	02/2001	Matsui et al.	
Lu	176	6,214,701	04/2001	Matsushita et al.	
Lu	177	6,225,192	05/2001	Aspar et al.	

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		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				
Lu	178	DE	0834363		03/1952			
	179	EP	0112 230	A1	04/1987			
	180	EP	0181249		06/1989			
	181	EP	0504714		09/1992			
	182	EP	0533551		03/1993			
	183	EP	0379828		09/1995			
	184	EP	0459177		12/1995			
	185	EP	0703609		03/1996			
	186	EP	0763849		03/1997			
	187	EP	807 970	A1	11/1997			
	188	EP	0867921		03/1998			
	189	EP	0867 917	A2	09/1998			
	190	EP	961 312	A2	12/1999			
	191	EP	084 287	A1	07/1983			
	192	EP	099 778	A1	02/1984			
	193	EP	155 875	A1	02/1984			
	194	EP	112 230	A1	04/1987			
	195	EP	164 281	A1	12/1985			
	196	EP	181 249	A1	06/1989			
	197	EP	0355913		12/1993			
	198	EP	0665588		12/1995			
	199	EP	0660140		06/1995			
Lee	200	EP	0665587		08/1995			
	201	FR	1558881		01/1969			

Examiner Signature	<i>Ksien Ming Lu</i>	Date Considered	6/22/05
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		Country Code <sup>2</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				
Lee	202	FR	2261802		02/1974			
	203	FR	2235474		04/1974			
	204	FR	2298880		01/1975			
	205	FR	2266304		04/1975			
	206	FR	2519437		01/1982			
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Examiner Signature	<i>Karen May Lee</i>	Date Considered	6/22/05
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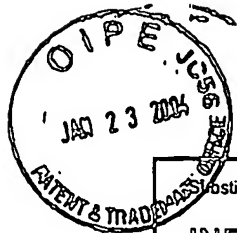


Substitute for form 1449A/PTO		<b>Complete if Known</b>			
		Application Number	10/644,644		
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Filing Date	August 19, 2003		
		First Named Inventor	Henley, Francois J.		
		Art Unit	Not Yet Assigned <b>2823</b>		
(use as many sheets as necessary)		Examiner Name	Not Yet Assigned <b>H LEE</b>		
Sheet	9	of	12	Attorney Docket Number	018419-000183US

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				
Lee	241	JP	2910001		01/1992			
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	254	WO	WO 99/35674		07/1999			

Examiner Signature	<i>Heer Ming Lu</i>	Date Considered	6/22/05
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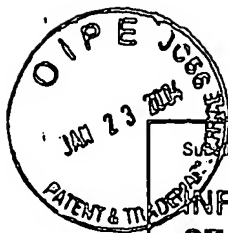
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				Art Unit	Not Yet Assigned 2823
				Examiner Name	Not Yet Assigned H. LEE
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Examiner Signature	<i>Kevin May Lee</i>	Date Considered	6/22/05
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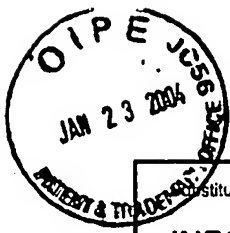
Substitute for form 1449B/PTO				<b>C mplete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				Application Number	10/644,644
				Filing Date	August 19, 2003
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				Application Number	10/644,644
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				First Named Inventor	Henley, Francois J.
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Lee	287	Veldkamp, W.B. et al., Binary Optics, Scientific American, pp. 50-55 (May 1992).	

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Examiner Signature	<i>Kevin Ming Lee</i>	Date Considered	<i>6/22/05</i>
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